



YEA SHIN TECHNOLOGY CO., LTD

YS50N03BA

N-Channel Enhancement MOSFET VDS = 30V, ID = 51A

(Pb) (H)

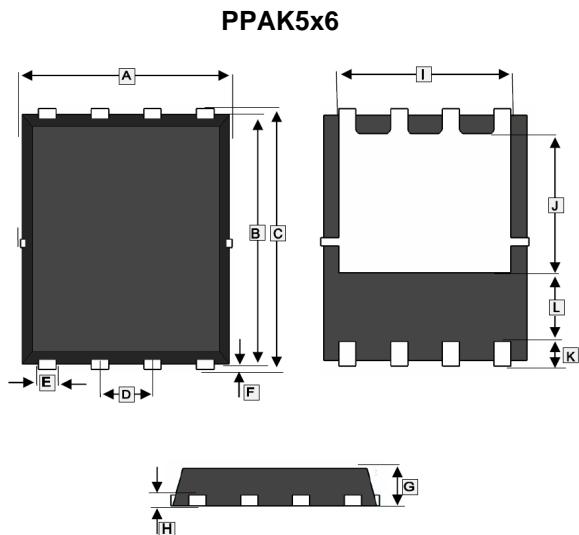
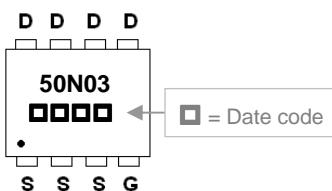
DESCRIPTION

The YS50N03BA provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness. The PPAK5x6 package is universally preferred for all commercial-industrial surface mount applications and suited for low voltage applications such as DC/DC converters.

FEATURES

- Lower Gate Charge
- Simple Drive Requirement
- Fast Switching Characteristic

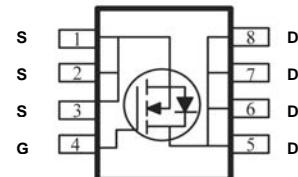
MARKING



REF.	Millimeter		REF.	Millimeter	
	Min.	Max.		Min.	Max.
A	4.8	5.1	G	0.8	1.1
B	5.7	5.9	H	0.254	Ref.
C	5.9	6.2	I	4.0	Ref.
D	1.27	BSC.	J	3.4	Ref.
E	0.33	0.51	K	0.6	Ref.
F	0.1	0.2	L	1.4	Ref.

PACKAGE INFORMATION

Package	MPQ	Leader Size
PPAK5x6	3K	13 inch



ABSOLUTE MAXIMUM RATINGS ($T_A=25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Rating	Unit	
Drain-Source Voltage	V_{DS}	30	V	
Gate-Source Voltage	V_{GS}	± 20	V	
Continuous Drain Current ¹ @ $V_{GS}=10\text{V}$	I_D	51	A	
		36	A	
		12	A	
		9.6	A	
Pulsed Drain Current ²	I_{DM}	130	A	
Single Pulse Avalanche Energy ³	E_{AS}	130	mJ	
Avalanche Current	I_{AS}	34	A	
Power Dissipation ⁴	$T_C=25^\circ\text{C}$	P_D	46	W
Operating Junction & Storage Temperature	T_J, T_{STG}	-55~150	°C	
Thermal Resistance Rating				
Thermal Resistance Junction-Ambient ¹ (Max).	$R_{\theta JA}$	62	°C / W	
Thermal Resistance Junction-Case ¹ (Max).	$R_{\theta JC}$	2.7	°C / W	

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ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Static						
Drain-Source Breakdown Voltage	BV_{DSS}	30	-	-	V	$\text{V}_{\text{GS}}=0, \text{I}_D=250\mu\text{A}$
Gate-Threshold Voltage	$\text{V}_{\text{GS}(\text{th})}$	1	-	2.5	V	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_D=250\mu\text{A}$
Forward Transconductance	g_{fs}	-	42	-	S	$\text{V}_{\text{DS}}=5\text{V}, \text{I}_D=30\text{A}$
Gate-Source Leakage Current	I_{GSS}	-	-	± 100	nA	$\text{V}_{\text{GS}}= \pm 20\text{V}$
Drain-Source Leakage Current	$\text{I}_{\text{DS}}^{\text{SS}}$	-	-	1	uA	$\text{V}_{\text{DS}}=24\text{V}, \text{V}_{\text{GS}}=0, T_J=25^\circ\text{C}$
		-	-	5		$\text{V}_{\text{DS}}=24\text{V}, \text{V}_{\text{GS}}=0, T_J=55^\circ\text{C}$
Static Drain-Source On-Resistance ²	$\text{R}_{\text{DS}(\text{ON})}$	-	-	9	mΩ	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_D=30\text{A}$
		-	-	13.5		$\text{V}_{\text{GS}}=4.5\text{V}, \text{I}_D=15\text{A}$
Gate Resistance	R_g	-	2.1	3.5	Ω	$f=1.0\text{MHz}$
Total Gate Charge	Q_g	-	10.6	-	nC	$\text{I}_D=15\text{A}$ $\text{V}_{\text{DS}}=15\text{V}$ $\text{V}_{\text{GS}}=4.5\text{V}$
Gate-Source Charge	Q_{gs}	-	4.2	-		
Gate-Drain ("Miller") Charge	Q_{gd}	-	4	-		
Turn-on Delay Time ²	$\text{T}_{\text{d}(\text{on})}$	-	6.4	-		
Rise Time	T_r	-	70.6	-	nS	$\text{V}_{\text{DD}}=15\text{V}$ $\text{I}_D=15\text{A}$ $\text{V}_{\text{GS}}=10\text{V}$ $\text{R}_G=3.3\Omega$
Turn-off Delay Time	$\text{T}_{\text{d}(\text{off})}$	-	22.4	-		
Fall Time	T_f	-	8	-		
Input Capacitance	C_{iss}	-	1127	-	pF	$\text{V}_{\text{GS}}=0$ $\text{V}_{\text{DS}}=15\text{V}$ $f=1.0\text{MHz}$
Output Capacitance	C_{oss}	-	194	-		
Reverse Transfer Capacitance	C_{rss}	-	77	-		
Guaranteed Avalanche Characteristics						
Single Pulse Avalanche Energy ⁵	EAS	45	-	-	mJ	$\text{V}_{\text{DD}}=25\text{V}, \text{L}=0.1\text{mH}, \text{I}_{\text{AS}}=20\text{A}$
Source-Drain Diode						
Diode Forward Voltage ²	V_{SD}	-	-	1	V	$\text{I}_S=1\text{A}, \text{V}_{\text{GS}}=0\text{V}$
Continuous Source Current ^{1,6}	I_S	-	-	51	A	$\text{V}_G=\text{V}_D=0$, Force Current
Pulsed Source Current ^{2,6}	I_{SM}	-	-	130	A	
Reverse Recovery Time	T_{rr}	-	12	-	nS	$\text{I}_F=30\text{A}, \frac{d\text{I}}{dt}=100\text{A}/\mu\text{s},$ $T_J=25^\circ\text{C}$
Reverse Recovery Charge	Q_{rr}	-	3.7	-	nC	

Note:

- The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper , $\leq 10\text{sec}$, $125^\circ\text{C}/\text{W}$ at steady state
- The data tested by pulsed , pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$
- The EAS data shows Max. rating . The test condition is $\text{V}_{\text{DD}}=25\text{V}, \text{V}_{\text{GS}}=10\text{V}, \text{L}=0.1\text{mH}, \text{I}_{\text{AS}}=34\text{A}$
- The power dissipation is limited by 150°C junction temperature
- The Min. value is 100% EAS tested guarantee.
- The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

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CHARACTERISTIC CURVES

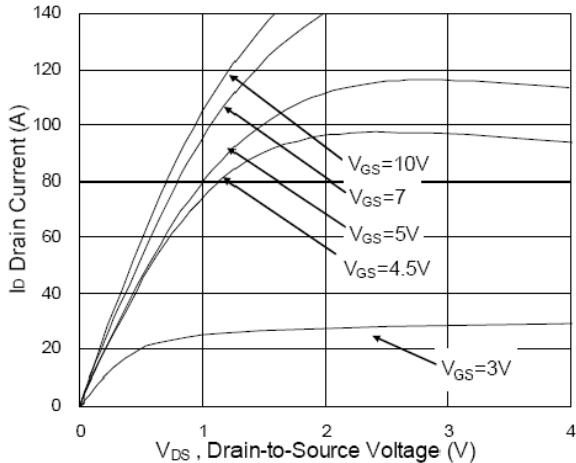


Fig.1 Typical Output Characteristics

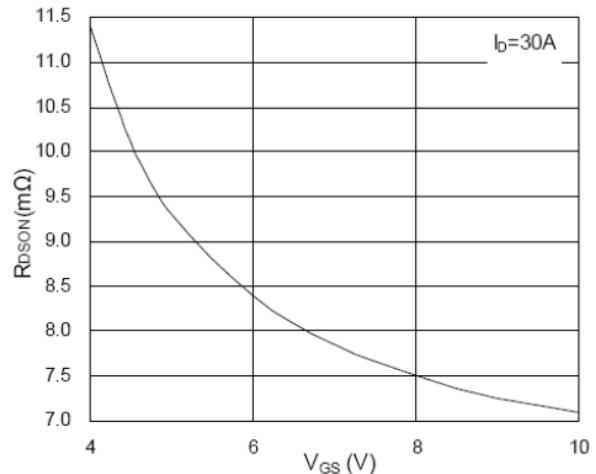


Fig.2 On-Resistance vs. Gate-Source

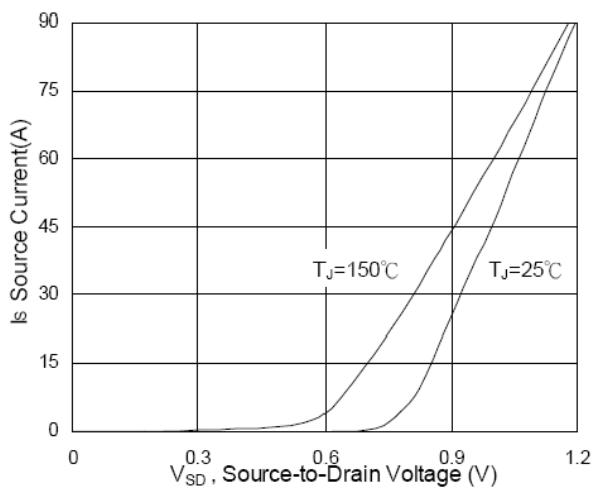


Fig.3 Forward Characteristics of Reverse

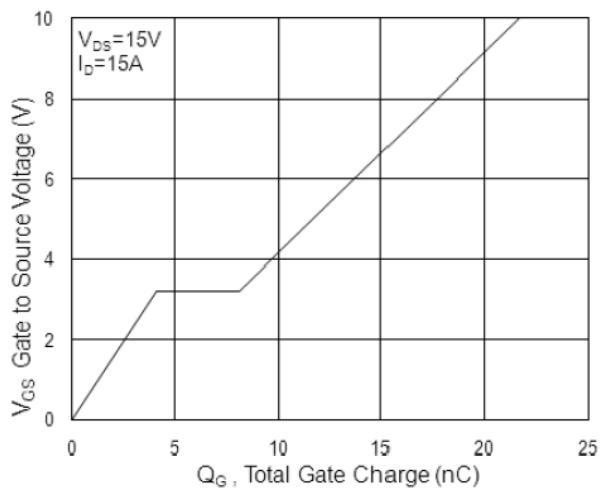


Fig.4 Gate-Charge Characteristics

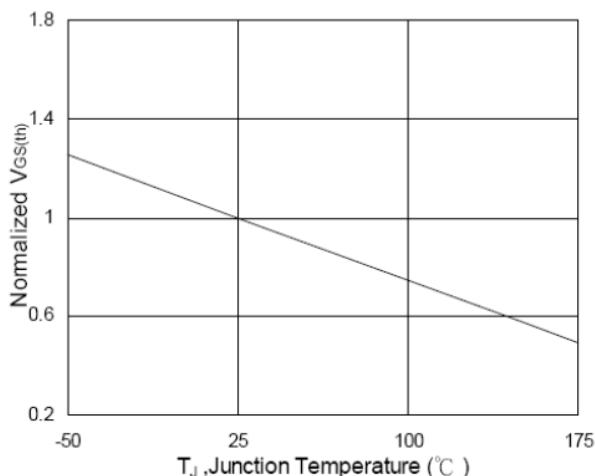


Fig.5 Normalized $V_{GS(th)}$ vs. T_J

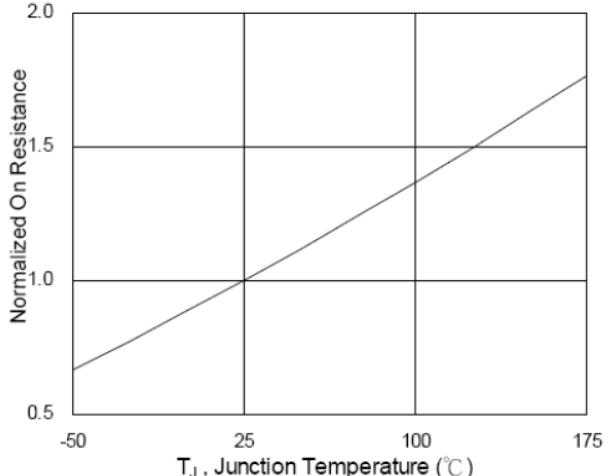


Fig.6 Normalized $R_{DS(on)}$ vs. T_J

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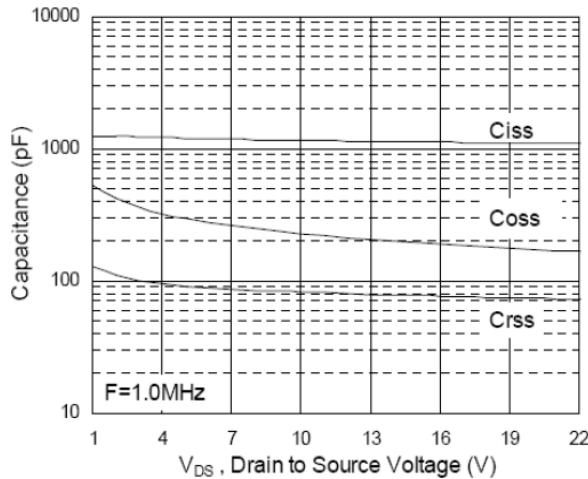


Fig.7 Capacitance

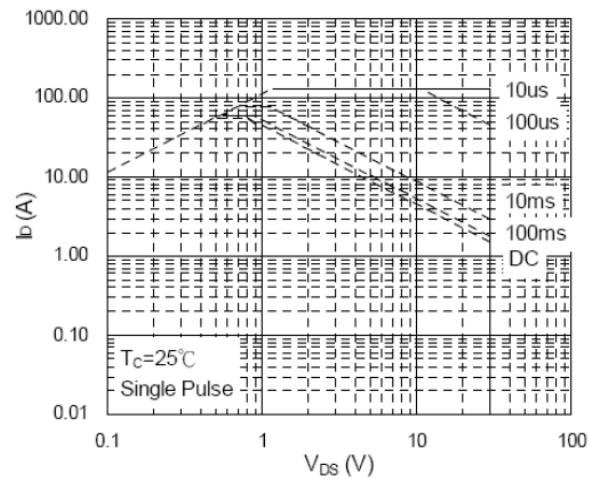


Fig.8 Safe Operating Area

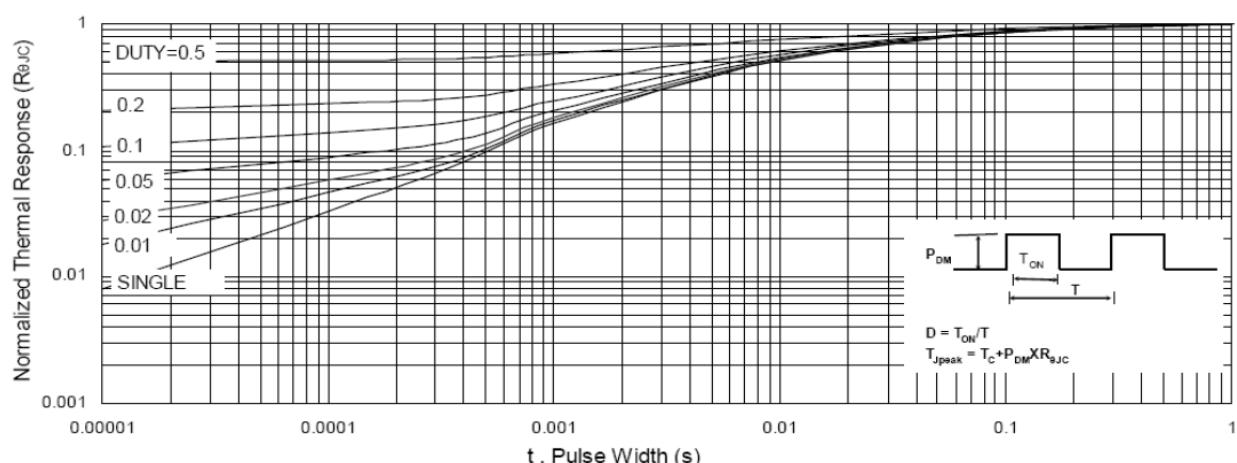


Fig.9 Normalized Maximum Transient Thermal Impedance

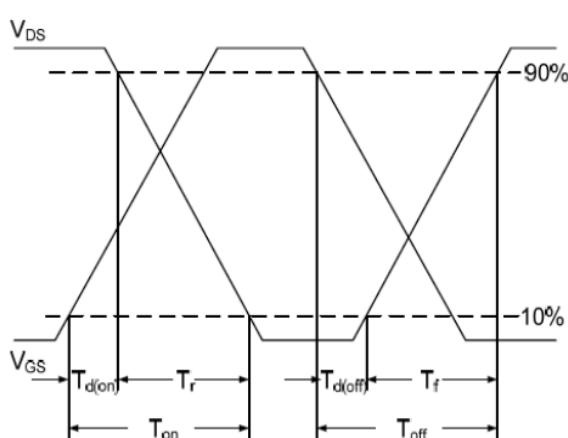


Fig.10 Switching Time Waveform

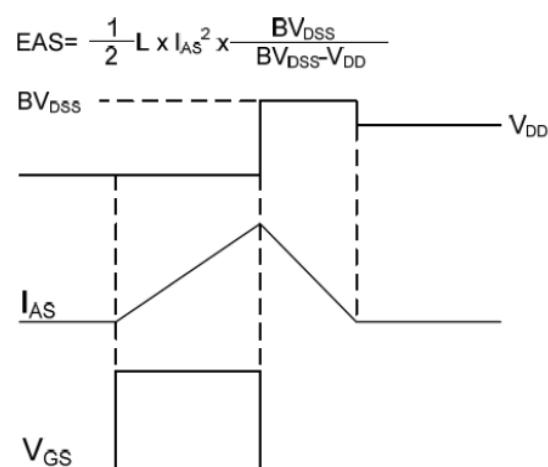


Fig.11 Unclamped Inductive Switching Waveform